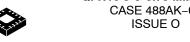
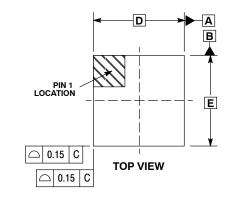
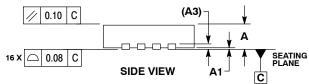
QFN16 3*3*0.75 MM, 0.5 P CASE 488AK-01 **ISSUE O**

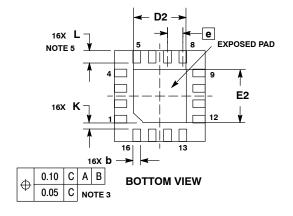


DATE 13 SEP 2004







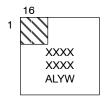


NOTES:

- DIMENSIONING AND TOLERANCING PER
- ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.
- 2. ODMINISTON BY APPLIES TO PLATED
 TERMINAL AND IS MEASURED BETWEEN
 0.25 AND 0.30 MM FROM TERMINAL
 4. COPLANARITY APPLIES TO THE EXPOSED
- PAD AS WELL AS THE TERMINALS. $L_{\rm max}$ CONDITION CAN NOT VIOLATE 0.2 MM SPACING BETWEEN LEAD TIP AND FLAG.

	MILLIMETERS		
DIM	MIN	MAX	
Α	0.70	0.80	
A1	0.00	0.05	
A3	0.20 REF		
b	0.18	0.30	
D	3.00 BSC		
D2	1.65	1.85	
E	3.00 BSC		
E2	1.65	1.85	
е	0.50 BSC		
K	0.20		
L	0.30	0.50	

GENERIC MARKING DIAGRAM*



XXXX = Specific Device Code Α = Assembly Location

= Wafer Lot L Υ = Year W = Work Week

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G", may or not be present.

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DESCRIPTION:	QFN16, 3*3*0.75 MM, 0.5 PITCH		PAGE 1 OF 1

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